

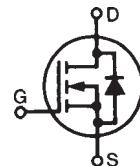
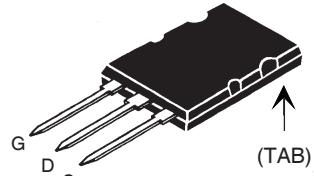
HiPerFET™ Power MOSFETs Q-Class

IXFB 72N55Q2

V_{DSS} = 550 V
I_{D25} = 72 A
R_{DS(on)} = 72 mΩ
t_{rr} ≤ 250 ns

N-Channel Enhancement Mode
Avalanche Rated, Low Q_g, Low Intrinsic R_g
High dV/dt, Low t_{rr}

Preliminary Data Sheet


PLUS 264™ (IXFB)


G = Gate D = Drain
S = Source TAB = Drain

Symbol	Test Conditions	Maximum Ratings		
V _{DSS}	T _J = 25°C to 150°C	550	V	
V _{DGR}	T _J = 25°C to 150°C; R _{GS} = 1 MΩ	550	V	
V _{GS}	Continuous	±30	V	
V _{GSM}	Transient	±40	V	
I _{D25}	T _c = 25°C	72	A	
I _{DM}	T _c = 25°C, pulse width limited by T _{JM}	284	A	
I _{AR}	T _c = 25°C	72	A	
E _{AR}	T _c = 25°C	60	mJ	
E _{AS}	T _c = 25°C	5.0	J	
dv/dt	I _s ≤ I _{DM} , di/dt ≤ 100 A/μs, V _{DD} ≤ V _{DSS} T _J ≤ 150°C, R _G = 2 Ω	20	V/ns	
P _D	T _c = 25°C	890	W	
T _J		-55 ... +150	°C	
T _{JM}		150	°C	
T _{stg}		-55 ... +150	°C	
T _L	1.6 mm (0.063 in.) from case for 10 s	300	°C	
F _c	Mounting Force	30...120/7.5...27	N/lb	
Weight		10	g	

Symbol	Test Conditions	Characteristic Values			
		(T _J = 25°C, unless otherwise specified)	min.	typ.	max.
V _{DSS}	V _{GS} = 0 V, I _D = 1mA	550			V
V _{GS(th)}	V _{DS} = V _{GS} , I _D = 8mA	2.5			5.0 V
I _{GSS}	V _{GS} = ±30 V, V _{DS} = 0				±200 nA
I _{DSS}	V _{DS} = V _{DSS} V _{GS} = 0 V	T _J = 25°C T _J = 125°C			100 μA 5 mA
R _{DS(on)}	V _{GS} = 10 V, I _D = 0.5 • I _{D25} Note 1				72 mΩ

Features

- Double metal process for low gate resistance
- Unclamped Inductive Switching (UIS) rated
- Low package inductance
 - easy to drive and to protect
- Fast intrinsic rectifier

Applications

- DC-DC converters
- Switched-mode and resonant-mode power supplies, >500kHz switching
- DC choppers
- Pulse generation
- Laser drivers

Advantages

- PLUS 264™ package for clip or spring mounting
- Space savings
- High power density

Symbol	Test Conditions	Characteristic Values			
		($T_J = 25^\circ\text{C}$, unless otherwise specified)	min.	typ.	max.
g_{fs}	$V_{DS} = 10 \text{ V}; I_D = 0.5 \cdot I_{D25}$ Note 1	40	57	S	
C_{iss} C_{oss} C_{rss}	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$	10500		pF	
		1500		pF	
		230		pF	
$t_{d(on)}$ t_r $t_{d(off)}$ t_f	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 \cdot V_{DSS}, I_D = 0.5 \cdot I_{D25}$ $R_G = 1 \Omega$ (External)	30		ns	
		23		ns	
		58		ns	
		10		ns	
$Q_{g(on)}$ Q_{gs} Q_{gd}	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 \cdot V_{DSS}, I_D = 0.5 \cdot I_{D25}$	258		nC	
		65		nC	
		123		nC	
R_{thJC}			0.14	K/W	
R_{thCK}		0.13		K/W	

Source-Drain Diode

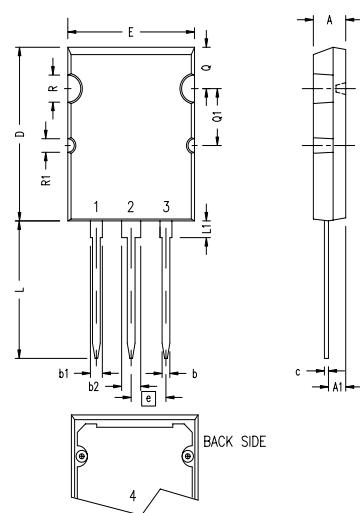
Characteristic Values

 $(T_J = 25^\circ\text{C}, \text{unless otherwise specified})$

Symbol	Test Conditions	min.	typ.	max.
I_s	$V_{GS} = 0 \text{ V}$		72	A
I_{SM}	Repetitive; pulse width limited by T_{JM}		288	A
V_{SD}	$I_F = I_s, V_{GS} = 0 \text{ V}$, Note 1		1.5	V
t_{rr} Q_{RM} I_{RM}	$I_F = 25 \text{ A}$ $-di/dt = 100 \text{ A}/\mu\text{s}$ $V_R = 100 \text{ V}$		250	ns
		1.2		μC
		8		A

Note: 1. Pulse test, $t \leq 300 \mu\text{s}$, duty cycle $d \leq 2 \%$

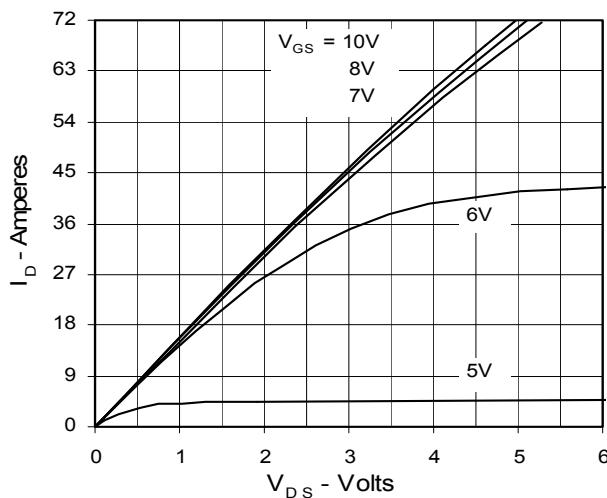
PLUS 264™ Outline



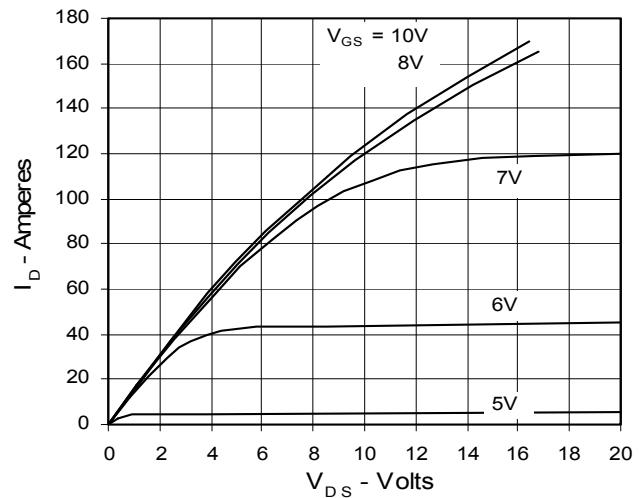
Terminals:
 1 - Gate
 2 - Drain (Collector)
 3 - Source (Emitter)
 4 - Drain (Collector)

SYM	INCHES	
	MIN	MAX
A	.185	.209
A1	.102	.118
b	.037	.055
b1	.087	.102
b2	.110	.126
c	.017	.029
D	1.007	1.047
E	.760	.799
e	.215 BSC	
L	.779	.842
L1	.087	.102
Q	.240	.256
Q1	.330	.346
$\emptyset R$.155	.187
$\emptyset R1$.085	.093

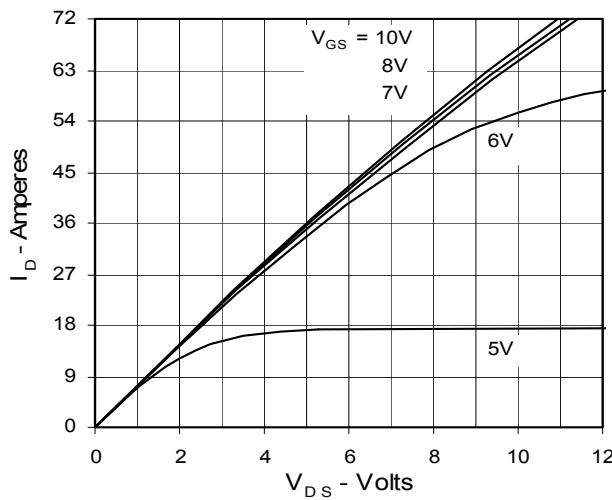
**Fig. 1. Output Characteristics
@ 25 Deg. C**



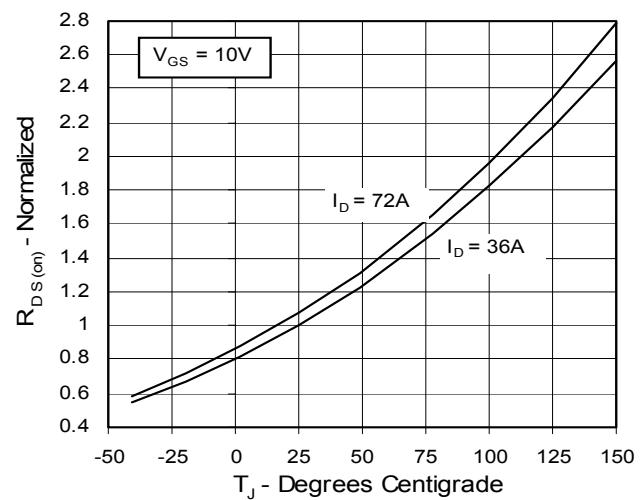
**Fig. 2. Extended Output Characteristics
@ 25 deg. C**



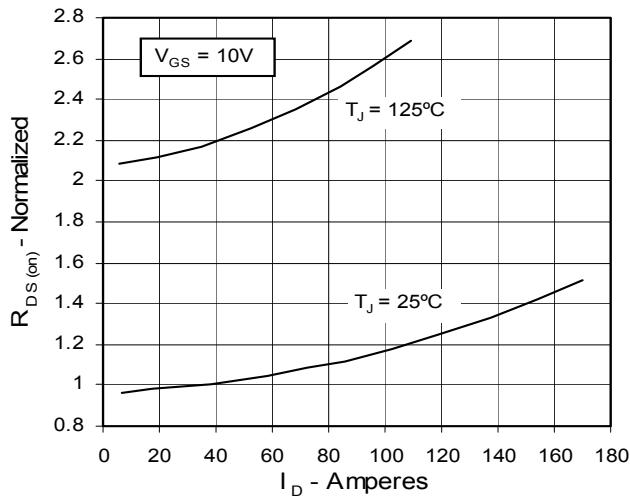
**Fig. 3. Output Characteristics
@ 125 Deg. C**



**Fig. 4. $R_{DS(on)}$ Normalized to I_{D25} Value vs.
Junction Temperature**



**Fig. 5. $R_{DS(on)}$ Normalized to I_{D25}
Value vs. I_D**



**Fig. 6. Drain Current vs. Case
Temperature**

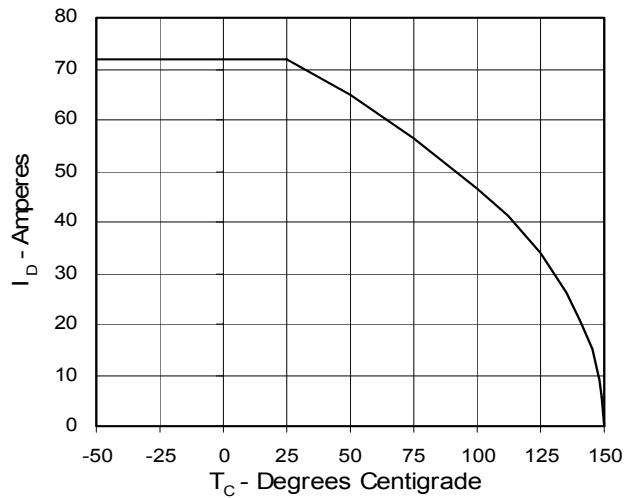
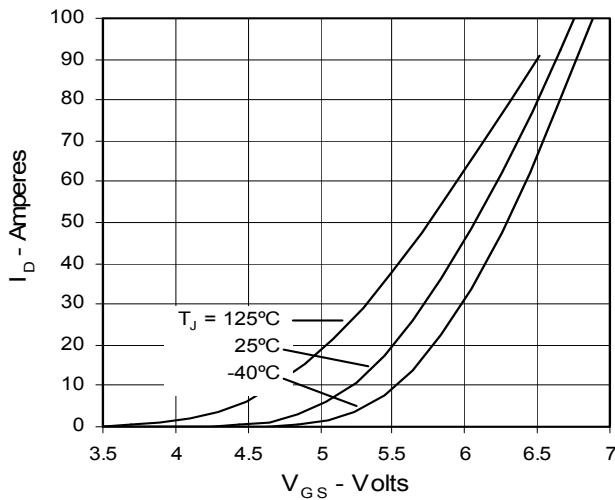
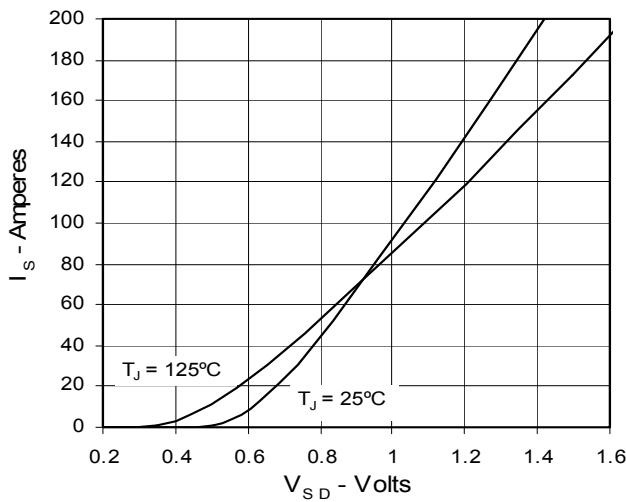
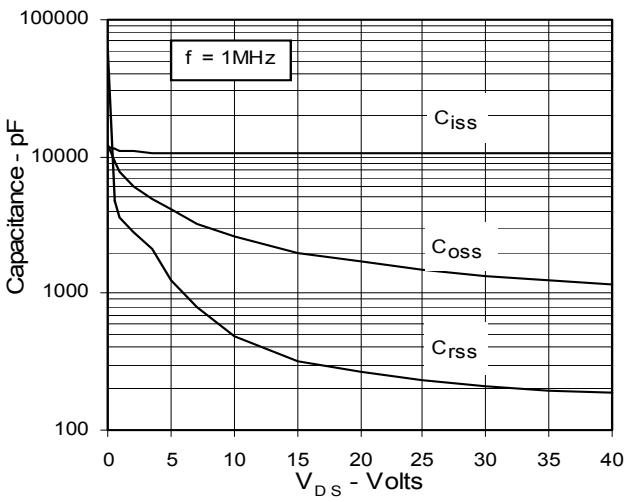
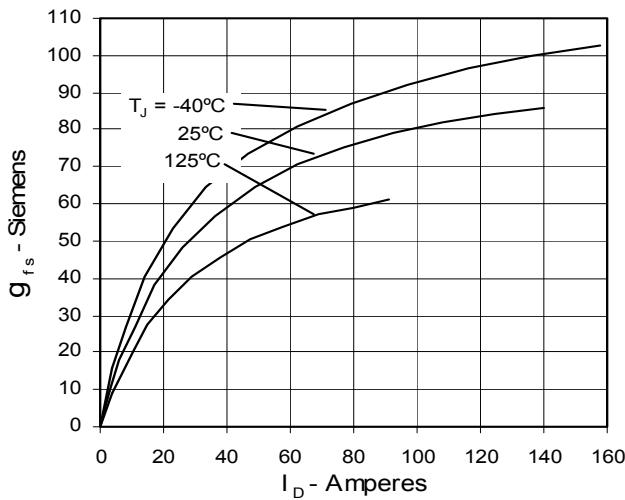
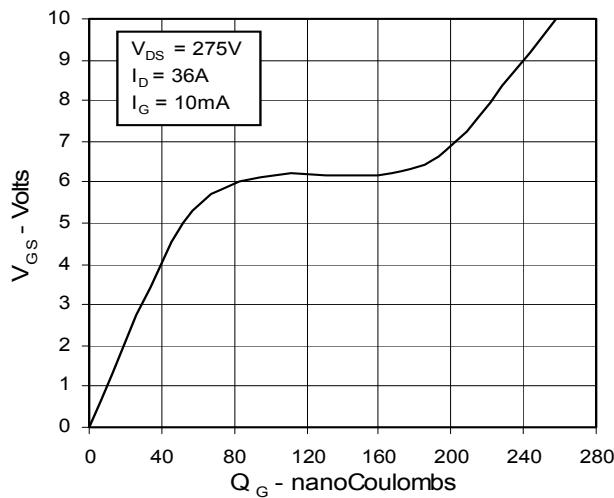
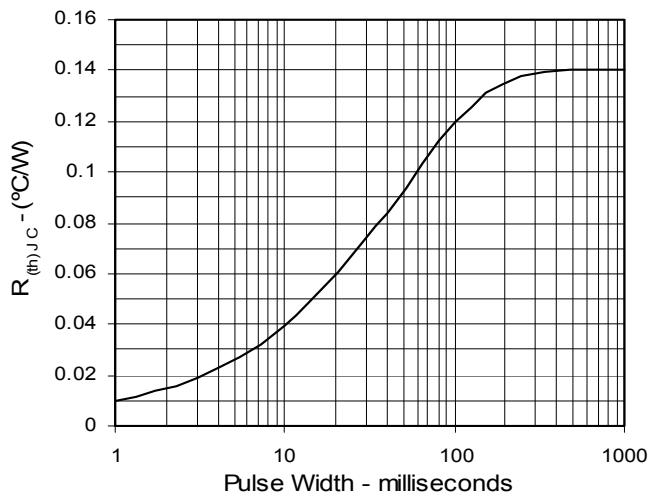


Fig. 7. Input Admittance

**Fig. 9. Source Current vs.
Source-To-Drain Voltage**

Fig. 11. Capacitance

Fig. 8. Transconductance

Fig. 10. Gate Charge

Fig. 12. Maximum Transient Thermal Resistance


IXYS reserves the right to change limits, test conditions, and dimensions.

IXYS MOSFETs and IGBTs are covered by one or more of the following U.S. patents:

4,835,592	4,881,106	5,017,508	5,049,961	5,187,117	5,486,715	6,306,728B1	6,259,123B1	6,306,728B1
4,850,072	4,931,844	5,034,796	5,063,307	5,237,481	5,381,025	6,404,065B1	6,162,665	6,534,343